Search Notes



Ap	plic	atio	n/Co	ntro	l No.
----	------	------	------	------	-------

10622498

Applicant(s)/Patent Under Reexamination

IWASAKI, TADASHI

Examiner

Art Unit

Hammond, Crystal L

2819

SEARCHED

Class	Subclass	Date	Examiner
326	30,86	09/24/2007	clh
327	108	09/24/2007	clh
326	30,86	1/3/2008	clh
327	108	1/3/2008	clh

SEARCH NOTES

Search Notes	Date	Examiner
consulted with Vibol Tan	09/24/2007	clh
EAST, IEEE, Google text searches	09/24/2007	clh
PLUS search	09/24/2007	clh
INSPEC and Dialog text searches	09/24/2007	clh
consulted with James Cho	1/3/2008	clh
updated EAST, IEEE, Google text searches	1/3/2008	clh
PLUS search	1/3/2008	clh

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
all	all	09/24/2007	clh
all	all	1/3/2008	clh

Part of Paper No.: 20080103